

SN55LVCP22 QML Q 类 2x2 1Gbps LVDS 交叉点开关

1 特性

- QML Q 类、SMD 5962-11242
- 高速 (高达 1000Mbps)
- 低抖动完全差分数据路径
- 50ps (典型值) 的峰峰值抖动, PRBS = 2²³-1 模式
- 总功率耗散少于 227mW (典型值), 313mW (最大值)
- 输出 (通道间) 延迟为 80ps (典型值)
- 可配置为 2:1 多路复用器, 1:2 多路信号分离器, 中继器或者 1:2 信号分配器
- 输入可接受 LVDS、LVPECL 和 CML 信号
- 1.7ns (典型值) 的快速交换时间
- 0.65ns (典型值) 的快速传播延迟
- 与 TIA/EIA-644-A LVDS 标准互操作
- 支持国防、航空航天和医疗应用:
 - 受控基线
 - 一个组装/测试厂和一个制造厂
 - 延长产品生命周期和延长产品变更通知
 - 产品可追溯性

2 应用

- 全球定位系统接收器
- 国防无线电
- 声纳

- 导引头前端
- 雷达

3 说明

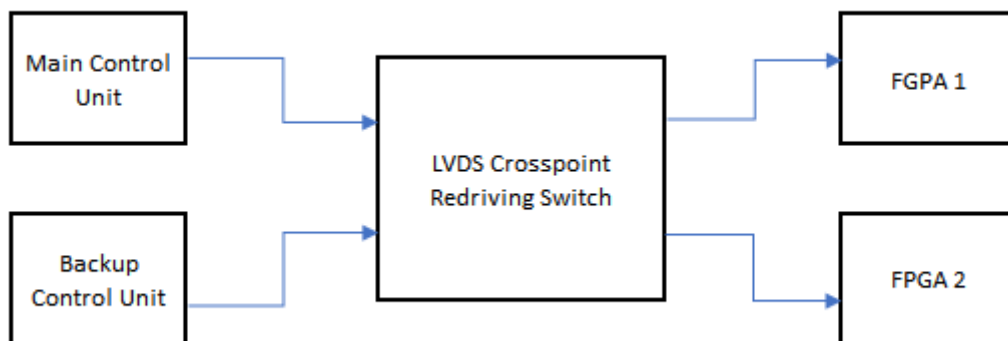
SN55LVCP22 是一款 2x2 交叉点开关, 使每个路径实现大于 1000Mbps 的运行速度。两个通道组装有宽共模 (0V 至 4V) 接收器, 从而实现对 LVDS、LVPECL 和 CML 信号的接收。两路输出为 LVDS 驱动器, 用于实现低功耗、低 EMI、高速运转。SN55LVCP22 器件支持 2:2 缓冲 (重复)、1:2 分配、2:1 复用、2x2 交换, 以及每个通道上的 LVPECL/CML 到 LVDS 电平转换。SN55LVCP22 的灵活运行可满足光网络、无线基础设施和数据通信系统中容错交换系统对于冗余串行总线传输的需求 (运转和保护交换卡)。

SN55LVCP22 使用一个完全差分数据路径来确保低噪声生成、快速交换时间、低脉宽失真和低抖动。80ps (典型值) 的输出通道间延迟确保所有应用中输出的准确一致。

器件信息

器件型号	等级	封装 ⁽¹⁾	封装尺寸 (标称值)
5962-112420 1QFA	QMLQ	CFP (16)	6.73mm x 10.3mm

(1) 如需了解所有可用封装, 请参阅数据表末尾的可订购产品附录。



简化版应用



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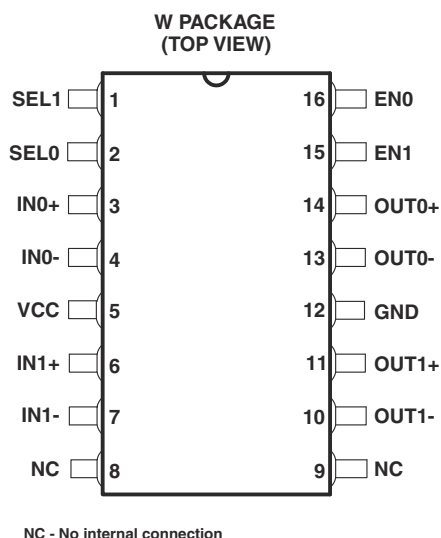
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4 Revision History

注：以前版本的页码可能与当前版本的页码不同

DATE	REVISION	NOTES
September 2020	*	Initial Release

5 Pin Configuration and Functions



Pin Functions

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
SEL1	1	Input	Switch Selection Control 1
SEL0	2	Input	Switch Selection Control 2
IN0+	3	Input	LVDS Receiver Positive Input 0
IN0-	4	Input	LVDS Receiver Negative Input 0
VCC	5	Power	3.3V Supply Voltage
IN1+	6	Input	LVDS Receiver Positive Input 1
IN1-	7	Input	LVDS Receiver Negative Input 1
NC	8	N/A	No Internal Connection
NC	9	N/A	No Internal Connection
OUT1-	10	Output	LVDS Driver Negative Output 1
OUT1+	11	Output	LVDS Driver Positive Output 1
GND	12	Ground	Ground
OUT0-	13	Output	LVDS Driver Negative Output 0
OUT0+	14	Output	LVDS Driver Positive Output 0
EN1	15	Input	Output Enable for Driver 1
EN0	16	Input	Output Enable for Driver 0

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted⁽¹⁾

	UNIT
Supply voltage ⁽²⁾ , V_{CC}	– 0.5 V to 4 V
CMOS/TTL input voltage (EN0, EN1, SEL0, SEL1)	– 0.5 V to 4 V
LVDS receiver input voltage (IN+, IN –)	– 0.7 V to 4.3 V
LVDS driver output voltage (OUT+, OUT –)	– 0.5 V to 4 V
LVDS output short circuit current	Continuous
Maximum Junction temperature	150°C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminals.

6.2 Handling Ratings

			MIN	MAX	UNIT
T _{stg}	Storage temperature range		-65	125	°C
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	-5000	5000	V
		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	-500	500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}	3	3.3	3.6	V
Receiver input voltage	0		4	V
Operating case (top) temperature, T_C ⁽¹⁾	– 55		125	°C
Magnitude of differential input voltage, $ V_{ID} $	0.1		3	V

- (1) Maximum case temperature operation is allowed as long as the device maximum junction temperature is not exceeded.

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		SN55LVCP22A-SP	UNIT
		W (CFP)	
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	118.1	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	51.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	107.2	°C/W
ψ_{JT}	Junction-to-top characterization parameter	28.4	°C/W
ψ_{JB}	Junction-to-board characterization parameter	95.1	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

over recommended operating conditions unless otherwise noted

PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
CMOS/TTL DC SPECIFICATIONS (EN0, EN1, SEL0, SEL1)					
V_{IH}	High-level input voltage	2	1.5	V_{CC}	V

over recommended operating conditions unless otherwise noted

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IL}	Low-level input voltage		GND	1.5	0.8	V
I _{IH}	High-level input current	V _{IN} = 3.6 V or 2.0 V, V _{CC} = 3.6 V	-25	±3	25	μA
I _{IL}	Low-level input current	V _{IN} = 0.0 V or 0.8 V, V _{CC} = 3.6 V	-15	±1	15	μA
V _{CL}	Input clamp voltage	I _{CL} = -18 mA		-0.8	-1.5	V

LVDS OUTPUT SPECIFICATIONS (OUT0, OUT1)

V _{OD}	Differential output voltage	R _L = 75 Ω, See 图 7-3	255	390	475	mV
		R _L = 75 Ω, V _{CC} = 3.3 V, T _A = 25°C, See 图 7-3	320	390	430	
Δ V _{OD}	Change in differential output voltage magnitude between logic states	V _{ID} = ±100 mV, See 图 7-3	-25		25	mV
V _{OS}	Steady-state offset voltage	See 图 7-4	1	1.2	1.45	V
ΔV _{OS}	Change in steady-state offset voltage between logic states	See 图 7-4	-25		25	mV
V _{OC(PP)}	Peak-to-peak common-mode output voltage	See 图 7-4		50		mV
I _{OZ}	High-impedance output current	V _{OUT} = GND or V _{CC}	-15		15	μA
I _{OFF}	Power-off leakage current	V _{CC} = 0 V, 1.5 V; V _{OUT} = 3.6 V or GND	-15		15	μA
I _{OS}	Output short-circuit current	V _{OUT+} or V _{OUT-} = 0 V			-8	mA
I _{OSB}	Both outputs short-circuit current	V _{OUT+} and V _{OUT-} = 0 V	-8		8	mA
C _O	Differential output capacitance	V _I = 0.4 sin(4E6 π t) + 0.5 V		3		pF

LVDS RECEIVER DC SPECIFICATIONS (IN0, IN1)

V _{TH}	Positive-going differential input voltage threshold	See 图 7-2 and 表 7-1			100	mV
V _{TL}	Negative-going differential input voltage threshold	See 图 7-2 and 表 7-1	-100			mV
V _{ID(HYS)}	Differential input voltage hysteresis			20	150	mV
V _{CMR}	Common-mode voltage range	V _{ID} = 100 mV, V _{CC} = 3.0 V to 3.6 V	0.05		3.95	V
I _{IN}	Input current	V _{IN} = 4 V, V _{CC} = 3.6 V or 0.0	-18	±1	18	μA
		V _{IN} = 0 V, V _{CC} = 3.6V or 0.0	-18	±1	18	
C _{IN}	Differential input capacitance	V _I = 0.4 sin(4E6 π t) + 0.5 V		3		pF

SUPPLY CURRENT

I _{CCQ}	Quiescent supply current	R _L = 75 Ω, EN0=EN1=High	60	87		mA
I _{CCD}	Total supply current	R _L = 75 Ω, C _L = 5 pF, 500 MHz (1000 Mbps), EN0=EN1=High	63	87		mA
I _{CCZ}	3-state supply current	EN0 = EN1 = Low	25	35		mA

(1) All typical values are at 25°C and with a 3.3-V supply.

6.6 Switching Characteristics

over recommended operating conditions unless otherwise noted

parameter		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{SET}	Input to SEL setup time	See 图 7-7		0.8	2.2	ns
t_{HOLD}	Input to SEL hold time	See 图 7-7		1.0	2.2	ns
t_{SWITCH}	SEL to switched output	See 图 7-7		1.7	2.6	ns
t_{PHZ}	Disable time, high-level-to-high-impedance	See 图 7-6		2	8	ns
t_{PLZ}	Disable time, low-level-to-high-impedance	See 图 7-6		2	8	ns
t_{PZH}	Enable time, high-impedance -to-high-level output	See 图 7-6		2	8	ns
t_{PZL}	Enable time, high-impedance-to-low-level output	See 图 7-6		2	8	ns
t_{LHT}	Differential output signal rise time (20%-80%) ⁽¹⁾	$C_L = 5$ pF, See 图 7-5		280	620	ps
t_{HLT}	Differential output signal fall time (20%-80%) ⁽¹⁾	$C_L = 5$ pF, See 图 7-5		280	620	ps
t_{JIT}	Added peak-to-peak jitter ⁽³⁾	$V_{ID} = 200$ mV, 50% duty cycle, $V_{CM} = 1.2$ V, 50 MHz, $C_L = 5$ pF		13.7	22.2	ps
		$V_{ID} = 200$ mV, 50% duty cycle, $V_{CM} = 1.2$ V, 240 MHz, $C_L = 5$ pF		13.4	24.5	
		$V_{ID} = 200$ mV, 50% duty cycle, $V_{CM} = 1.2$ V, 500 MHz, $C_L = 5$ pF		14.4	35.7	
		$V_{ID} = 200$ mV, PRBS = $2^{15}-1$ data pattern, $V_{CM} = 1.2$ V, 240 Mbps, $C_L = 5$ pF		68.3	204	ps
		$V_{ID} = 200$ mV, PRBS = $2^{15}-1$ data pattern, $V_{CM} = 1.2$ V, 1000 Mbps, $C_L = 5$ pF		73.2	282	
t_{Jrms}	Added random jitter (rms) ⁽³⁾	$V_{ID} = 200$ mV, 50% duty cycle, $V_{CM} = 1.2$ V, 50 MHz, $C_L = 5$ pF		0.97	1.5	pSRMS
		$V_{ID} = 200$ mV, 50% duty cycle, $V_{CM} = 1.2$ V, 240 MHz, $C_L = 5$ pF		0.85	1.53	
		$V_{ID} = 200$ mV, 50% duty cycle, $V_{CM} = 1.2$ V, 500 MHz, $C_L = 5$ pF		0.86	1.79	
t_{PLHD}	Propagation delay time, low-to-high-level output ⁽¹⁾		200	650	2350	ps
t_{PHLD}	Propagation delay time, high-to-low-level output ⁽¹⁾		200	650	2350	ps
$t_{skew}^{(5)}$	Pulse skew ($ t_{PLHD} - t_{PHLD} $) ⁽²⁾	$C_L = 5$ pF, See 图 7-5		45	160	ps
t_{CCS}	Output channel-to-channel skew, splitter mode	$C_L = 5$ pF, See 图 7-5		80		ps
$f_{MAX}^{(5)}$	Maximum operating frequency ⁽⁴⁾		1			GHz

(1) Input: $V_{IC} = 1.2$ V, $V_{ID} = 200$ mV, 50% duty cycle, 1 MHz, $t_r/t_f = 500$ ps

(2) t_{skew} is the magnitude of the time difference between the t_{PLHD} and t_{PHLD} of any output of a single device.

(3) Not production tested.

(4) Signal generator conditions: 50% duty cycle, t_r or $t_f \leq 100$ ps (10% to 90%), transmitter output criteria: duty cycle = 45% to 55% $V_{OD} \geq 300$ mV.

(5) t_{skew} and f_{MAX} parameters are guaranteed by characterization, but not production tested.

6.7 Typical Characteristics

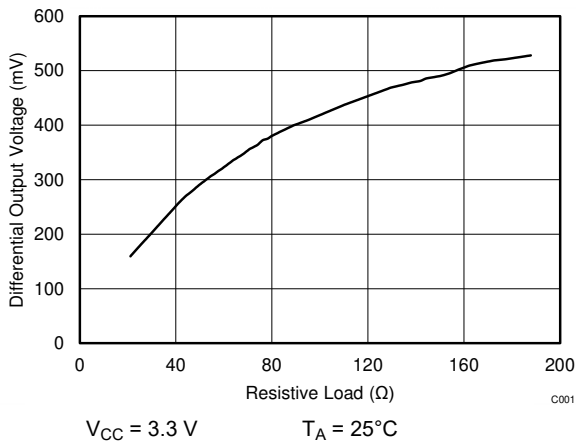


图 6-1. Differential Output Voltage vs Resistive Load

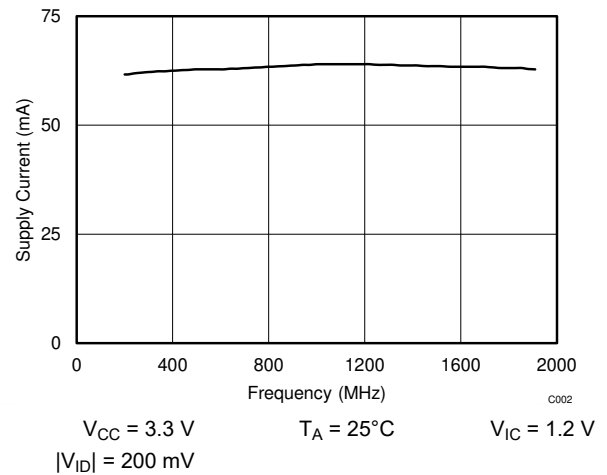


图 6-2. Supply Current vs Frequency

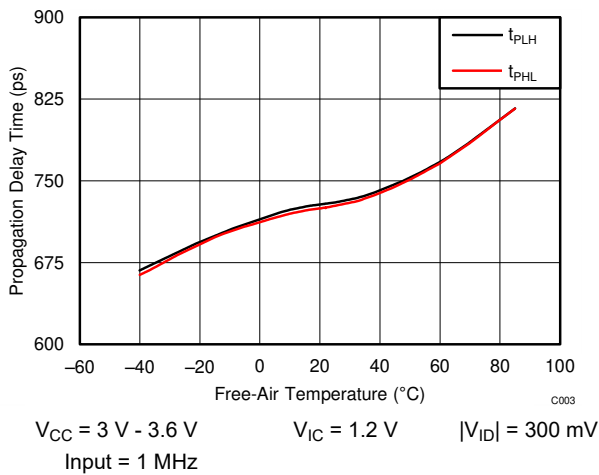


图 6-3. Propagation Delay Time vs Free-Air Temperature

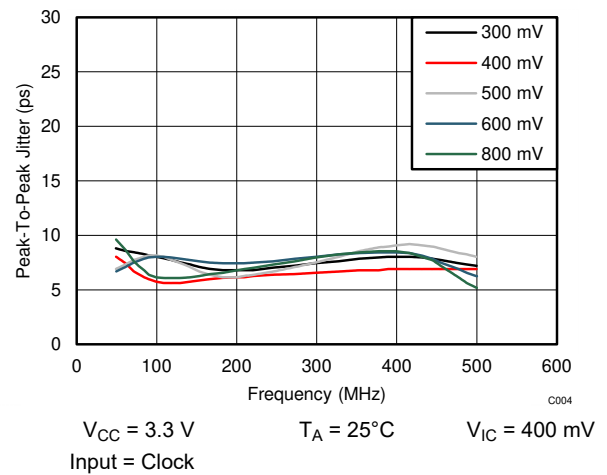


图 6-4. Peak-To-Peak Jitter vs Frequency

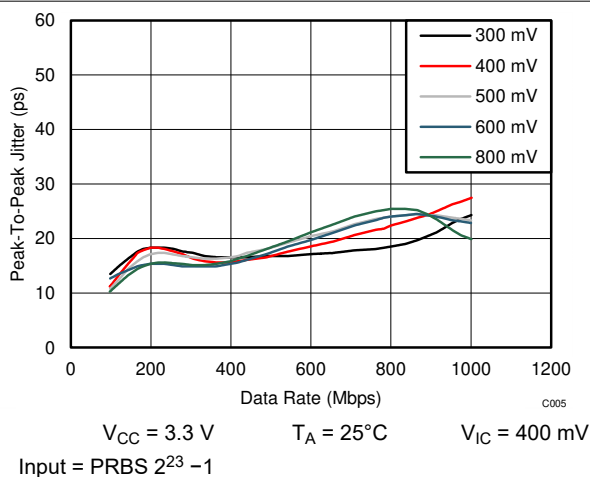


图 6-5. Peak-To-Peak Jitter vs Data Rate

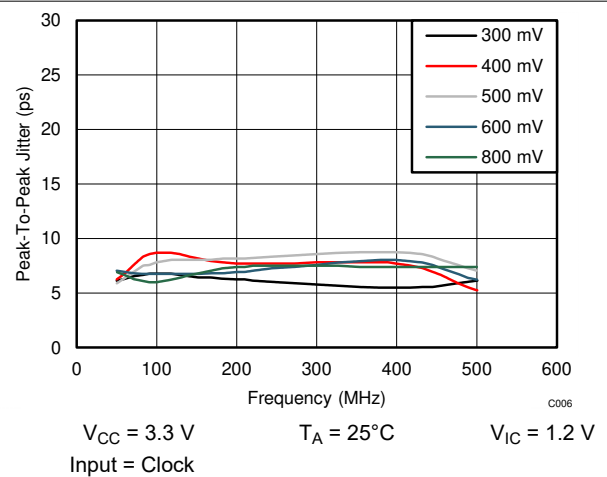


图 6-6. Peak-To-Peak Jitter vs Frequency

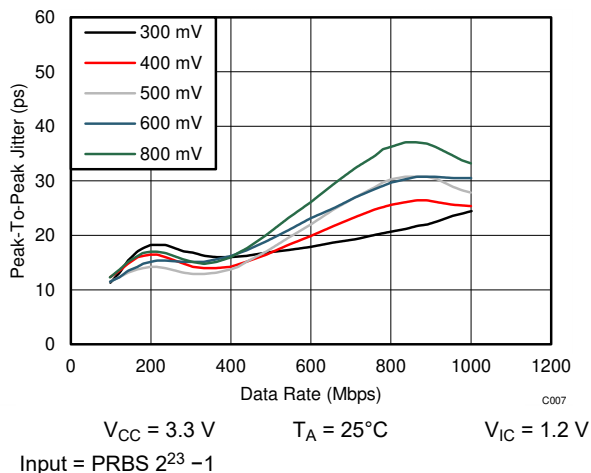


图 6-7. Peak-To-Peak Jitter vs Data Rate

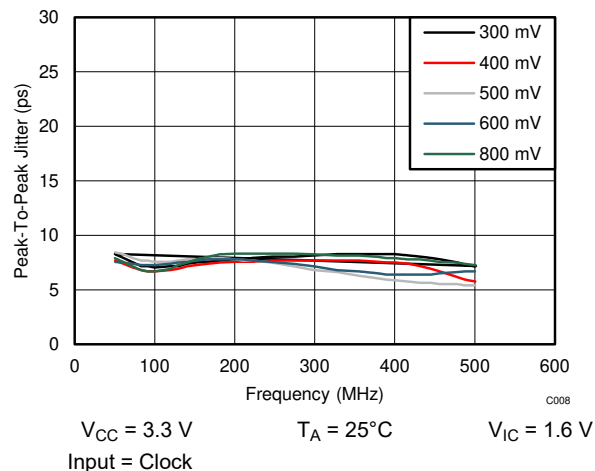


图 6-8. Peak-To-Peak Jitter vs Frequency

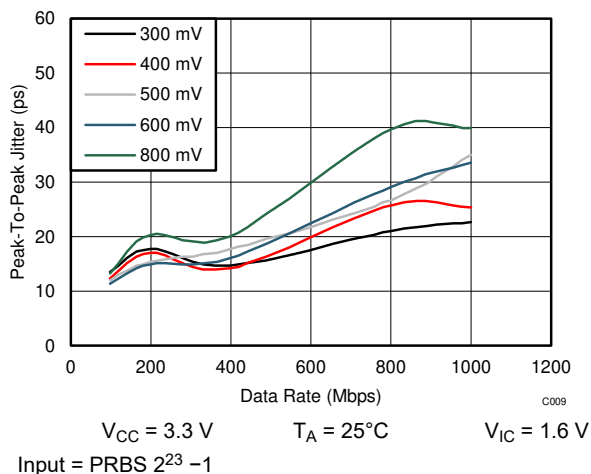


图 6-9. Peak-To-Peak Jitter vs Data Rate

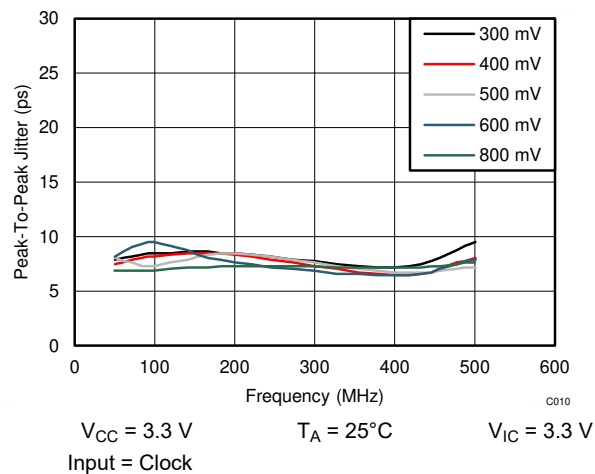


图 6-10. Peak-To-Peak Jitter vs Frequency

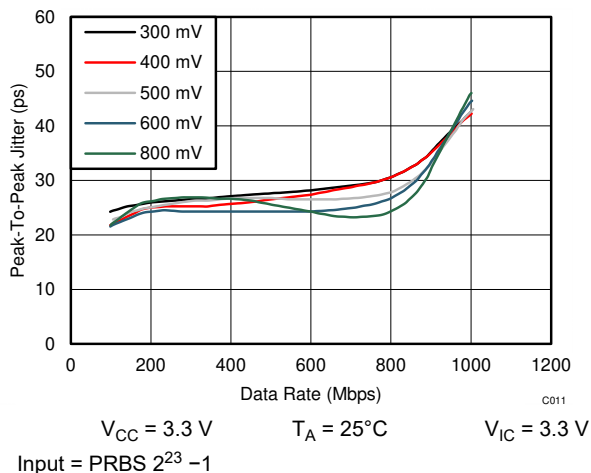


图 6-11. Peak-To-Peak Jitter vs Data Rate

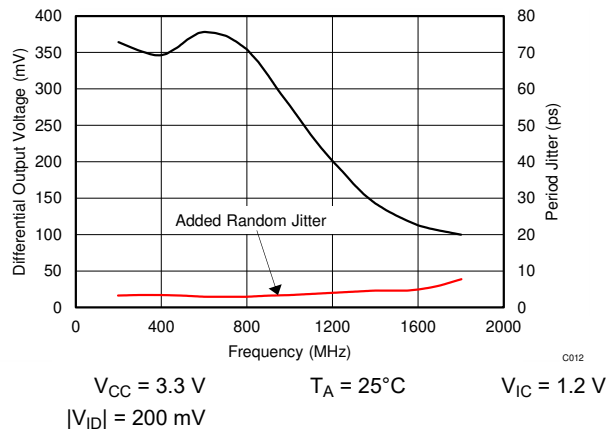
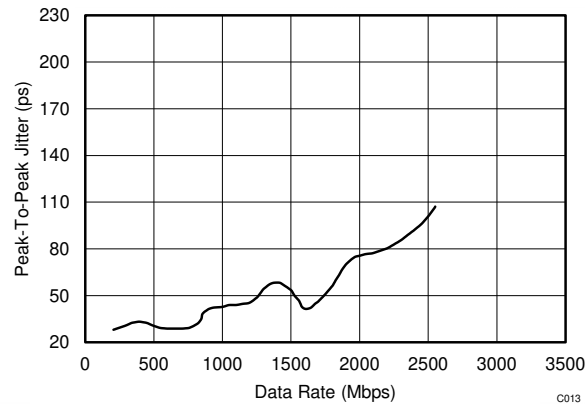


图 6-12. Differential Output Voltage vs Frequency



$V_{CC} = 3.3\text{ V}$
 $|V_{ID}| = 200\text{ mV}$

$T_A = 25^\circ\text{C}$
Input = PRBS $2^{23} - 1$

$V_{IC} = 1.2\text{ V}$

图 6-13. Peak-To-Peak Jitter vs Data Rate

7 Parameter Measurement Information

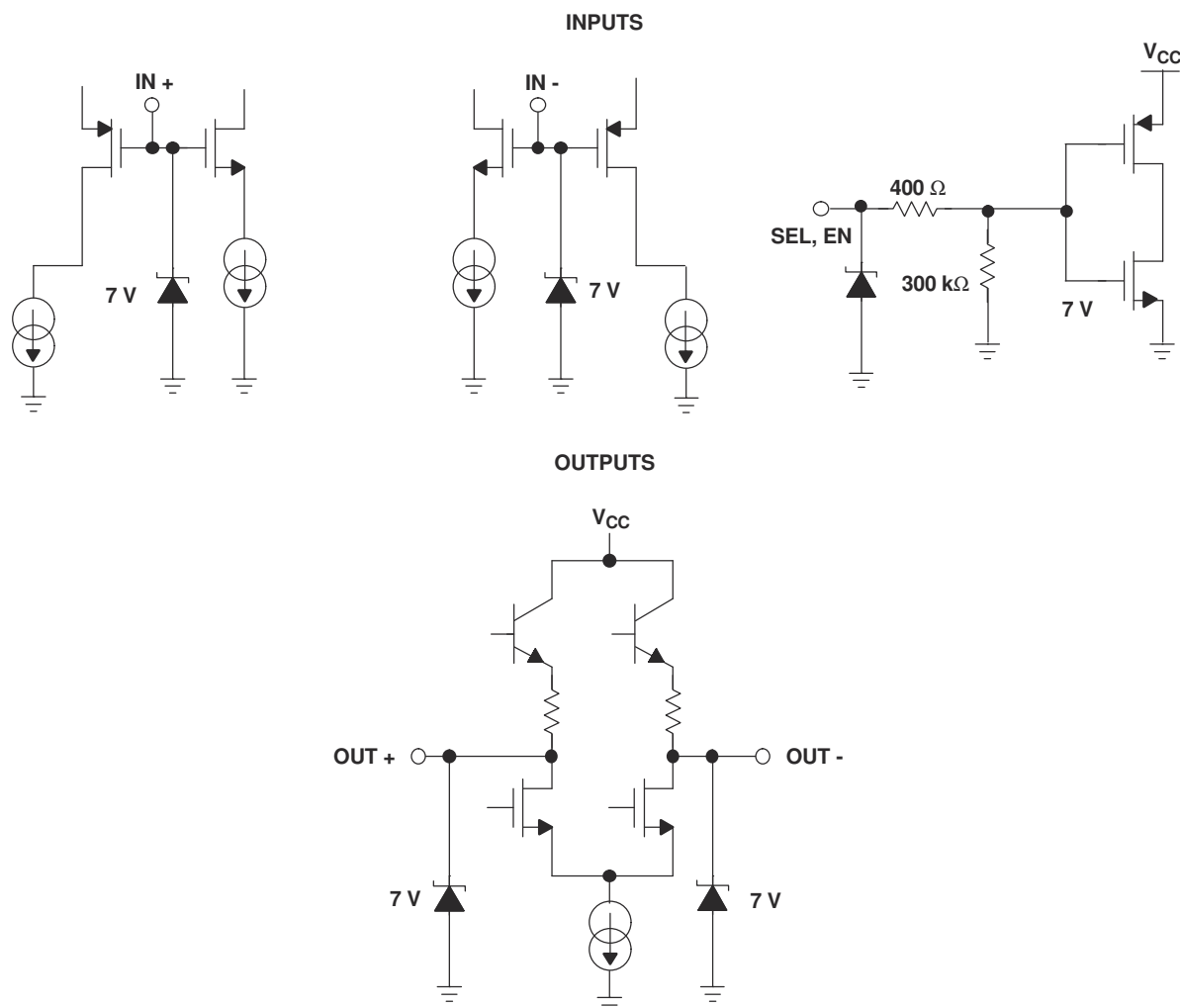


图 7-1. Equivalent Input and Output Schematic Diagrams

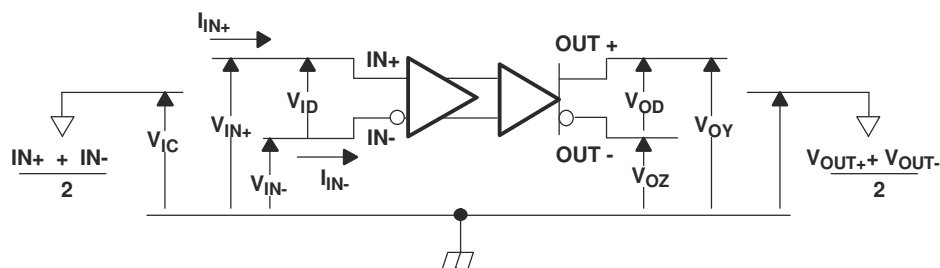


图 7-2. Voltage And Current Definitions

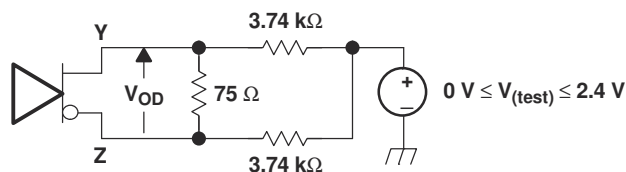
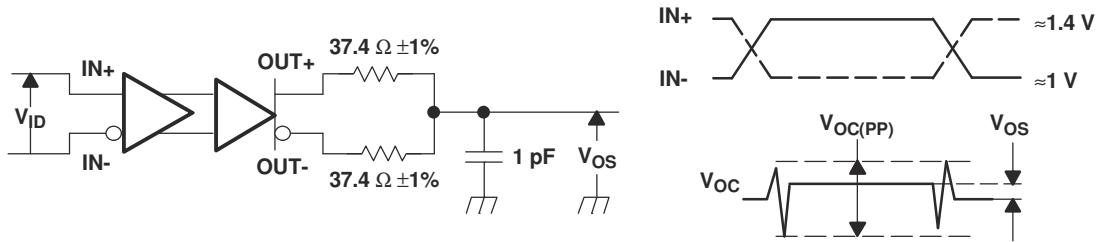
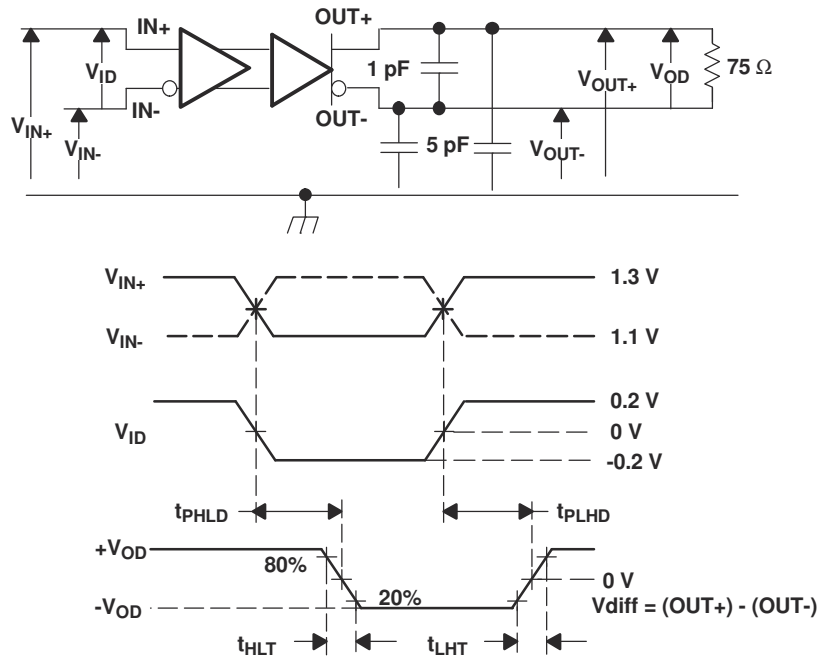


图 7-3. Differential Output Voltage (V_{OD}) Test Circuit



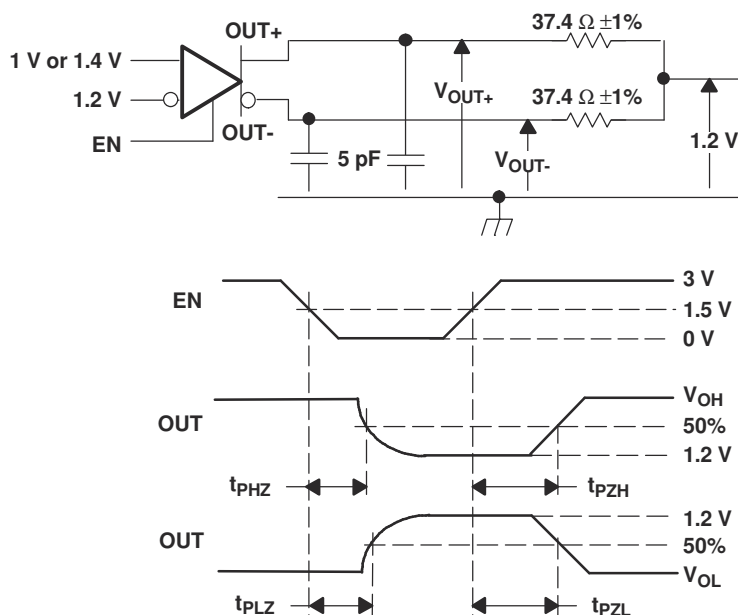
All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \leq 1$ ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns; $R_L = 100 \Omega$; C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.; the measurement of $V_{OC(PP)}$ is made on test equipment with a -3 dB bandwidth of at least 300 MHz.

图 7-4. Test Circuit And Definitions For The Driver Common-Mode Output Voltage



All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \leq .25$ ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns. C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

图 7-5. Timing Test Circuit And Waveforms



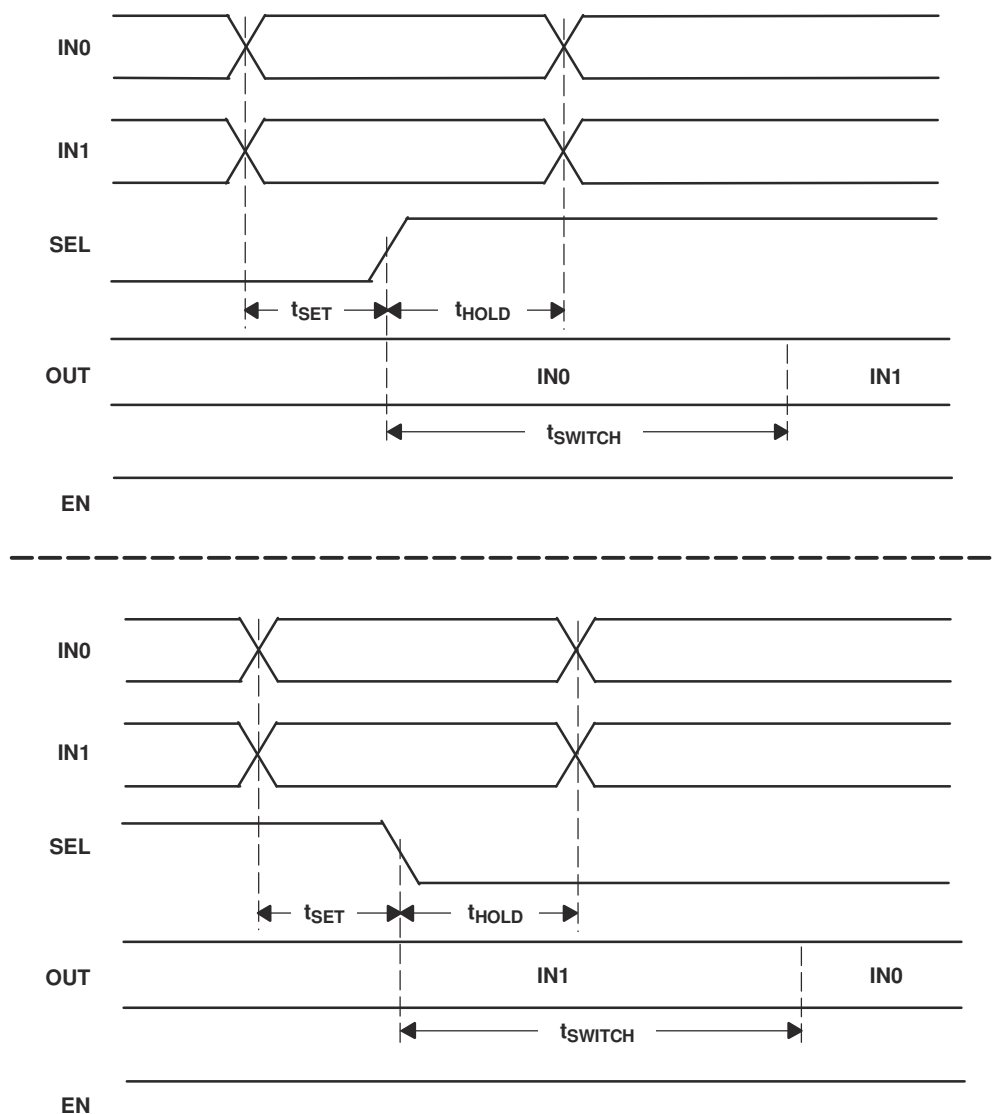
All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \leq 1$ ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns. C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

图 7-6. Enable And Disable Time Circuit And Definitions

表 7-1. Receiver Input Voltage Threshold Test

APPLIED VOLTAGES		RESULTING DIFFERENTIAL INPUT VOLTAGE	RESULTING COMMON- MODE INPUT VOLTAGE	OUTPUT ⁽¹⁾
V_{IA}	V_{IB}	V_{ID}	V_{IC}	
1.25 V	1.15 V	100 mV	1.2 V	H
1.15 V	1.25 V	- 100 mV	1.2 V	L
4.0 V	3.9 V	100 mV	3.95 V	H
3.9 V	4.0 V	- 100 mV	3.95 V	L
0.1 V	0.0 V	100 mV	0.05 V	H
0.0 V	0.1 V	- 100 mV	0.05 V	L
1.7 V	0.7 V	1000 mV	1.2 V	H
0.7 V	1.7 V	- 1000 mV	1.2 V	L
4.0 V	3.0 V	1000 mV	3.5 V	H
3.0 V	4.0 V	- 1000 mV	3.5 V	L
1.0 V	0.0 V	1000 mV	0.5 V	H
0.0 V	1.0 V	- 1000 mV	0.5 V	L

(1) H = high level, L = low level



t_{SET} and t_{HOLD} times specify that data must be in a stable state before and after mux control switches.

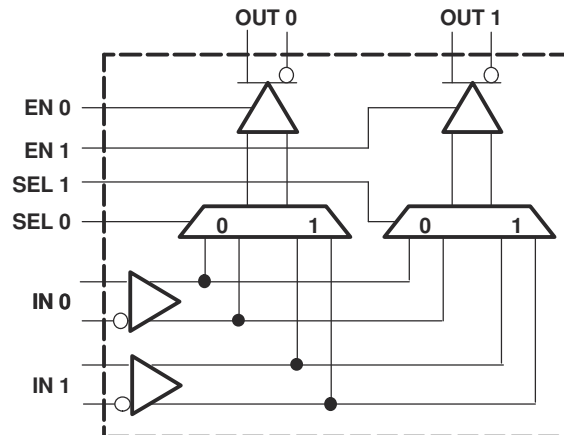
图 7-7. Input To Select For Both Rising And Falling Edge Setup And Hold Times

8 Detailed Description

8.1 Overview

The SN55LVCP22 is a high-speed 1-Gbps 2x2 LVDS redriving cross-point switch that can be used in mux or demux or splitter configurations. The SN55LVCP22 provides multiple signal switching options that allow system implementation flexibility as described in 表 8-1. The SN55LVCP22 incorporates wide common-mode (0 V to 4 V) receivers, allowing for the receipt of LVDS, LVPECL, and CML signals and low-power LVDS drivers to provide high-speed operations. The SN55LVCP22 uses a fully differential data path to ensure low-noise generation, fast switching times, low pulse width distortion, and low jitter.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Input Select Pins

SEL0 pin selects which differential input lane will be routed to Lane 0 driver differential output OUT0 and SEL1 pin selects which differential input lane will be routed to Lane 1 driver differential output OUT1

8.3.2 Output Enable Pins

EN0 pin is an active high enable for OUT0 driver differential output and EN1 pin is an active high enable for OUT1 driver differential output.

8.4 Device Functional Modes

表 8-1. Function Table

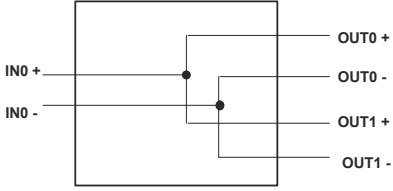
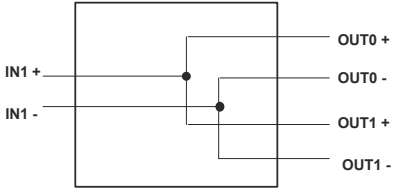
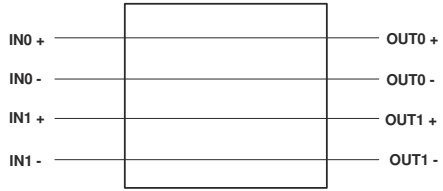
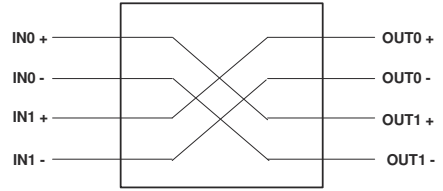
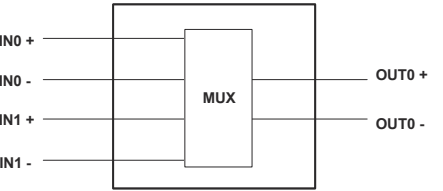
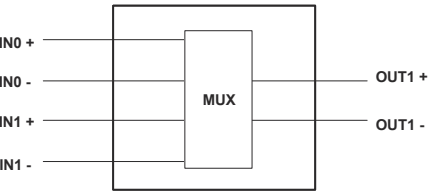
SEL0	SEL1	EN0	EN1	OUT0	OUT1	FUNCTION	SIGNAL FLOW
0	0	1	1	IN0	IN0	1:2 Splitter Input IN0	 Diagram showing a 1:2 Splitter where the differential input IN0+ and IN0- are connected to the inputs of a crossbar switch. The switch routes the signals to the differential outputs OUT0+ and OUT0- (Lane 0) and OUT1+ and OUT1- (Lane 1).
1	1	1	1	IN1	IN1	1:2 Splitter Input IN1	 Diagram showing a 1:2 Splitter where the differential input IN1+ and IN1- are connected to the inputs of a crossbar switch. The switch routes the signals to the differential outputs OUT0+ and OUT0- (Lane 0) and OUT1+ and OUT1- (Lane 1).

表 8-1. Function Table (continued)

SEL0	SEL1	EN0	EN1	OUT0	OUT1	FUNCTION	SIGNAL FLOW
0	1	1	1	IN0	IN1	2-lane Repeater	Dual Repeater 
1	0	1	1	IN1	IN0	Cross-switch	2 X 2 Crosspoint 
0	X	1	0	IN0	High-Z	2:1 Mux Output OUT0	2:1 Mux 
1				IN1			
X	0	0	1	High-Z	IN0	2:1 Mux Output OUT1	2:1 Mux 
	1			High-Z	IN1		

9 Application and Implementation

9.1 Application Information

The SN55LVCP22 can support different kind of signaling at the receiver with proper termination network. The output drivers will output LVDS differential signals.

9.2 Typical Application

9.2.1 Low-Voltage Positive Emitter-Coupled Logic (LVPECL)

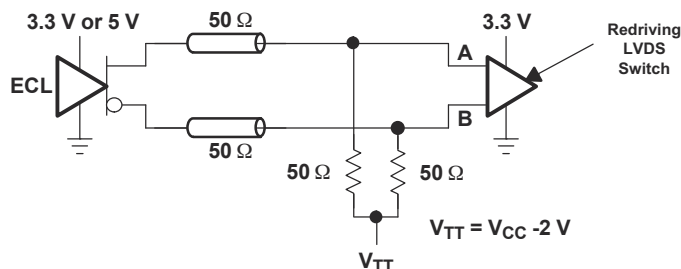


图 9-1. Low-Voltage Positive Emitter-Coupled Logic (LVPECL)

9.2.1.1 Design Requirements

表 9-1. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
Single-ended termination	50 Ω
V_{TT} termination voltage	$V_{CC} - 2 V$

9.2.1.2 Detailed Design Procedure

Use two 50 Ω termination resistors (as close to the input pins as possible) with termination voltage of V_{TT} as described in 图 9-1 to receive LVPECL input signals.

9.2.2 Current-Mode Logic (CML)

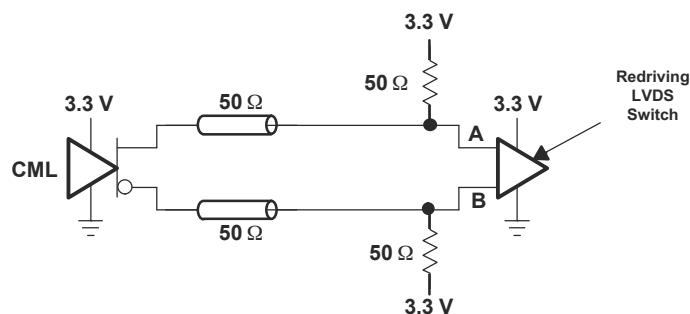


图 9-2. Current-Mode Logic (CML)

9.2.2.1 Design Requirements

表 9-2. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
Single-ended termination	50 Ω
Termination Voltage	$V_{CC} = 3.3V$

9.2.2.2 Detailed Design Procedure

Use two 50 Ω termination resistors (as close to the input pin as possible) with termination voltage of V_{CC} as described in 图 9-2 to receive CML input signals.

9.2.3 Single-Ended (LVPECL)

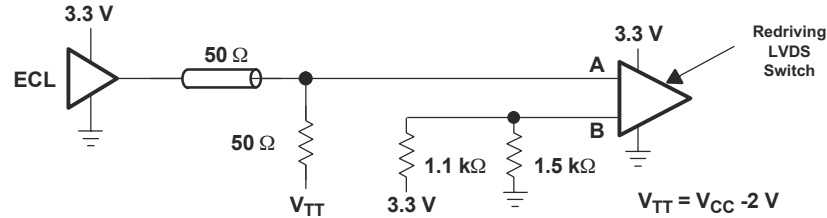


图 9-3. Single-Ended (LVPECL)

9.2.3.1 Design Requirements

表 9-3. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
Single-ended termination for input used	50 Ω
V_{TT} termination voltage	$V_{CC} - 2\text{ V}$
Unused input pull-up termination to V_{CC}	1.1 k Ω
Unused input pull-down termination to Ground	1.5 k Ω

9.2.3.2 Detailed Design Procedure

Use a 50 Ω termination resistor (as close to the input pin as possible) with termination voltage of V_{TT} as described in 图 9-3 to receive Single-ended LVPECL input signals. Terminate Unused input pin with 1.1 k Ω pull-up to V_{CC} and 1.5 k Ω pull-down to ground.

9.2.4 Low-Voltage Differential Signaling (LVDS)

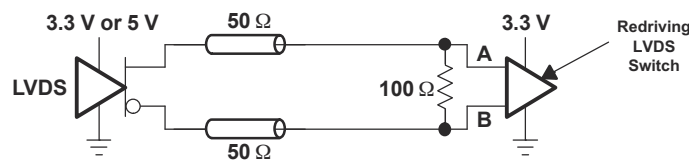


图 9-4. Low-Voltage Differential Signaling (LVDS)

9.2.4.1 Design Requirements

表 9-4. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
Differential Termination	100 Ω

9.2.4.2 Detailed Design Procedure

Use a 100 Ω differential termination resistor (as close to the input pins as possible) as described in 图 9-4 to receive LVDS input signals.

9.2.5 Application Curves

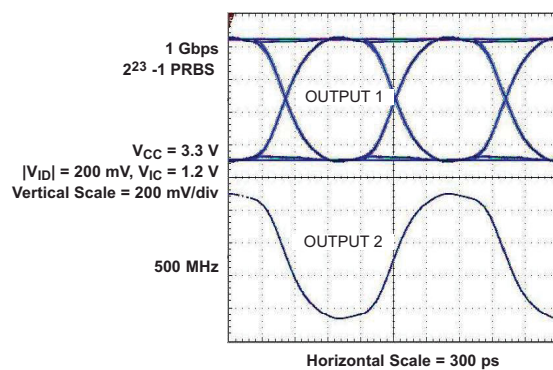


图 9-5. LVDS Output

10 Power Supply Recommendations

There is no power supply sequence required for SN55LVCP22. It is recommended that at least a 0.1uF decoupling capacitor is placed at the device VCC near the pin.

11 Layout

11.1 Layout Guidelines

High performance layout practices are paramount for board layout for high speed signals to ensure good signal integrity. Even minor imperfection can cause impedance mismatch resulting reflection. Special care is warranted for traces, connections to device, and connectors.

11.2 Layout Example

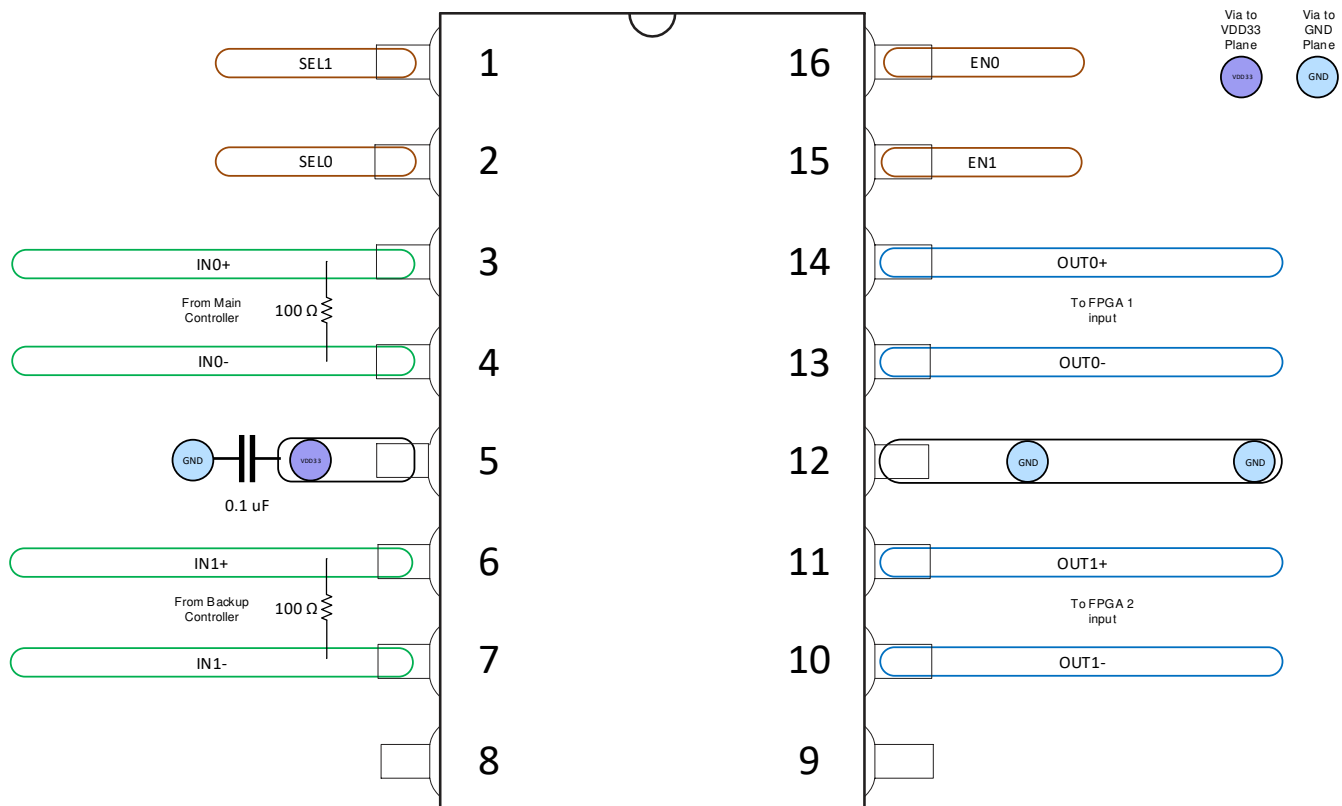


图 11-1. Layout Example with LVDS input signals

12 Device and Documentation Support

12.1 Trademarks

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12.2 静电放电警告



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ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

12.3 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
5962-1124201QFA	Active	Production	CFP (W) 16	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-1124201QF A LVCP22W-SP

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF SN55LVCP22 :

- Space : [SN55LVCP22-SP](#)

NOTE: Qualified Version Definitions:

- Space - Radiation tolerant, ceramic packaging and qualified for use in Space-based application

W (R-GDFP-F16)

CERAMIC DUAL FLATPACK



4040180-3/F 04/14

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